

■ IEEE EDS Kansai Chapter IMFEDK Best Paper Award

Paper ID: C-3
Titled: *“Demonstration of High Channel Mobility in 4H-SiC MOSFETs by Utilizing Phosphorus-Doped Gate Oxide”*
Authors: **Dai Okamoto**, H. Yano, K. Hirata, S. Kotake, T. Hatayama, T. Fuyuki
Affiliation: Nara Institute of Science and Technology

■ IEEE EDS Kansai Chapter IMFEDK Student Paper Award

Author: **Yosuke Tojo**¹, Paper ID: PA-4
Titled: *“Location Controls of Crystallized Areas in Silicon Films Utilizing Cage Shape Protein”*
Coauthors: A. Miura^{1,2}, I. Yamashita^{1,3,4}, Y. Uraoka^{1,4},
Affiliation: ¹Nara Institute of Science and Technology, ²National Chiao Tung University, ³Panasonic, ⁴CREST

Author: **Hideo Shimizu**, Paper ID: PA-12
Titled: *“Reduction of self-heating effect in silicon MOSFETs on directly bonded Si-on-SiC wafer with high heat conductance ”*
Coauthor: R. Araki, H. Shinohara, H. Kinoshita, M. Yoshimoto
Affiliation: Kyoto Institute of Technology

Author: **Daishi Ino**, Paper ID: PA-16
Titled: *“Performance Evaluation of 1-V Deep Sub-micron Dynamic-Threshold SOI MOSFET”*
Coauthors: T. Tochio, Y. Omura
Affiliation: Kansai University

Author: **Yuta Goto**, Paper ID: PB-4
Titled: *“Chemical Bonding Features at TiO₂/Pt Interface and Their Impact on Resistance-Switching Properties”*
Coauthors: A. Ohta, H. Murakami, S. Higashi, S. Miyazaki
Affiliation: Hiroshima University

Author: **Kumiho Tsuji**, Paper ID: PC-4
Titled: *“Micro-fabrication and characterization of an ion-sensitive ZnO-based transistor on a glass substrate”*
Coauthors: K. Koike, K. Ogata, S. Sasa, M. Inoue, M. Yano
Affiliation: Osaka Institute of Technology